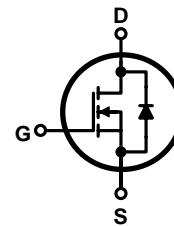
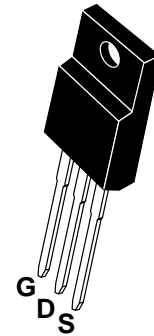
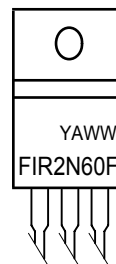


**PIN Connection TO-220F**
**Switchng Regulator Application**
**Features**

- High Voltage:  $BV_{DSS}=600V(\text{Min.})$
- Low  $C_{rss}$  :  $C_{rss}=3.4F(\text{Typ.})$
- Low gate charge :  $Q_g=7.0nC(\text{Typ.})$
- Low  $R_{DS(on)}$  :  $R_{DS(on)}=7.0\Omega(\text{Max.})$


**Marking Diagram**


- Y = Year
- A = Assembly Location
- WW = Work Week
- FIR2N60F = Specific Device Code

**Absolute maximum ratings ( $T_c=25^\circ\text{C}$  unless otherwise noted) Advanced N-Ch Power MOSFET**

Characteristic Symbol		Rating	Unit
Drain-source voltage	$V_{DSS}$	600	V
Gate-source voltage	$V_{GSS}$	$\pm 20$	V
Drain current (DC) *	$I_D$	( $T_c=25^\circ\text{C}$ )	1.5
		( $T_c=100^\circ\text{C}$ )	1
Drain current (Pulsed) *	$I_{DM}$	6.0	A
Power dissipation	$P_D$	19.1	W
Avalanche current (Single) ②	$I_{AS}$	2.0	A
Single pulsed avalanche energy ②	$E_{AS}$	88	mJ
Avalanche current (Repetitive) ①	$I_{AR}$	2.0	A
Repetitive avalanche energy ①	$E_{AR}$	8	mJ
Junction temperature	$T_J$	150	$^\circ\text{C}$
Storage temperature range	$T_{stg}$	-55~150	

\* Limited by maximum junction temperature

Characteristic Symbol		Typ.	Max.	Unit
Thermal resistance	Junction-case R	$th(J-C)$	5.6	$^\circ\text{C}/\text{W}$
	Junction-ambient R	$th(J-A)$	100	

**Electrical Characteristics** ( $T_C=25^\circ\text{C}$  unless otherwise noted)

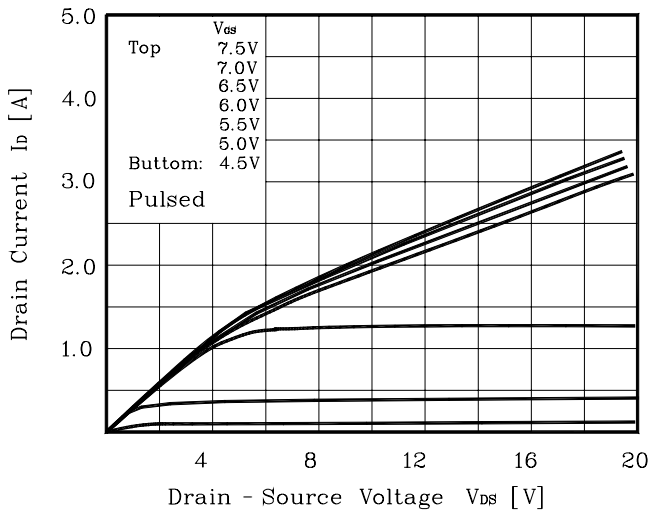
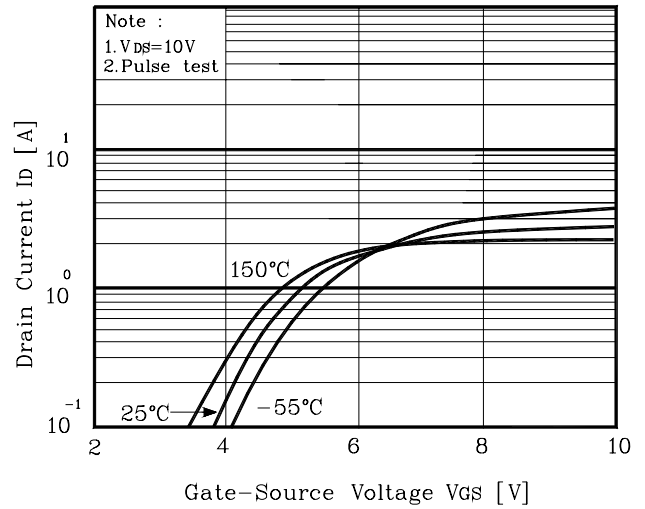
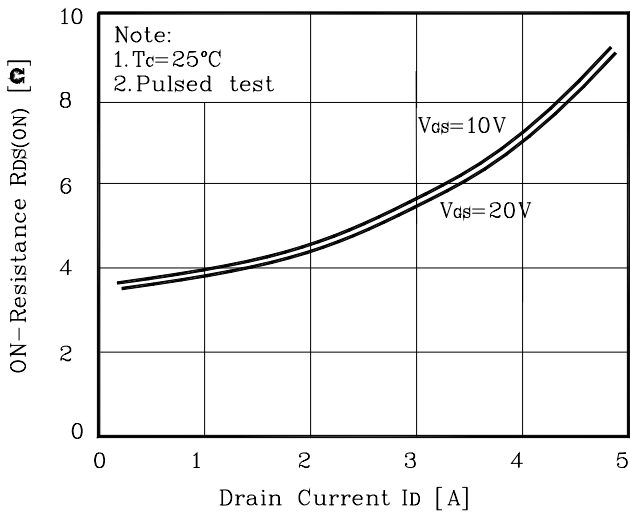
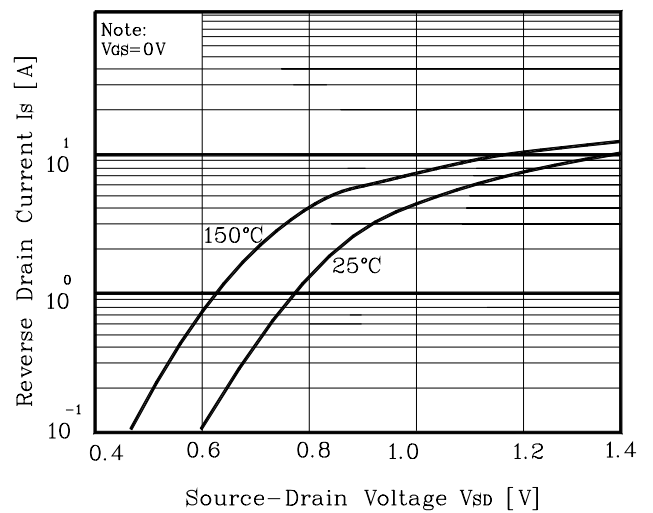
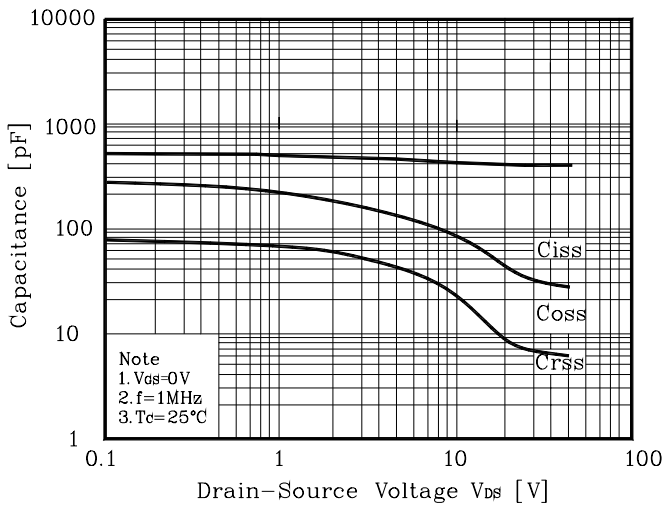
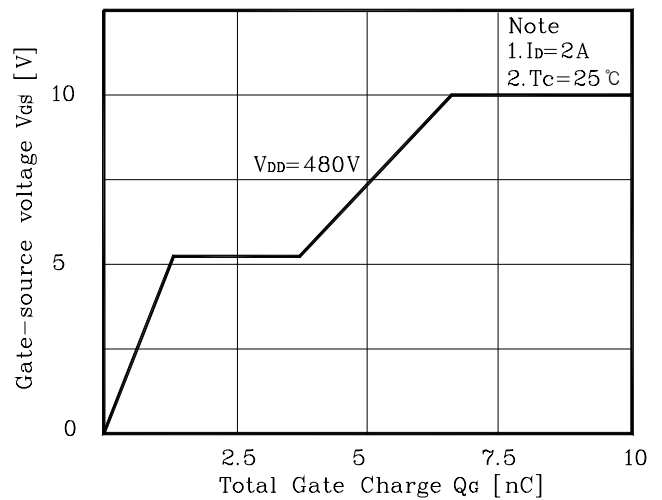
Characteristic Symbol		Test Condition	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	$BV_{DSS}$	$I_D=250\mu\text{A}, V_{GS}=0$ 600		-	-	V
Gate threshold voltage	$V_{GS(th)}$	$I_D=250\mu\text{A}, V_{DS}=V_{GS}$	2.0	3.0	4.0	
Drain-source cut-off current	$I_{DSS}$	$V_{DS}=600\text{V}, V_{GS}=0\text{V}$ -		-	25	$\mu\text{A}$
Gate leakage current	$I_{GSS}$	$V_{DS}=0\text{V}, V_{GS}=\pm 30\text{V}$	- -		$\pm 100$	nA
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}, I_D=1.0\text{A}$ -		7.0	8.0	$\Omega$
Forward transfer conductance	$g_{fs}$	$V_{DS}=10\text{V}, I_D=1.0\text{A}$	-	5	-	S
Input capacitance	$C_{iss}$ -	$V_{GS}=0\text{V}, V_{DS}=25\text{V},$ $f=1\text{MHz}$		170	-	pF
Output capacitance	$C_{oss}$		-	27	-	
Reverse transfer capacitance	$C_{rss}$		-	5	-	
Turn-on delay time	$t_{d(on)}$	$V_{DD}=300\text{V}, I_D=1.5\text{A}$ $R_G=4.7\Omega$	-	8	-	ns
Rise time	$t_r$ -			30	-	
Turn-off delay time	$t_{d(off)}$		-	22	-	
Fall time	$t_f$		- 55		-	
Total gate charge	$Q_g$ -	$V_{DS}=480\text{V}, V_{GS}=10\text{V}$ $I_D=1.5\text{A}$		7.5		nC
Gate-source charge	$Q_{gs}$ -			1.7	-	
Gate-drain charge	$Q_{gd}$		- 4.	0	-	

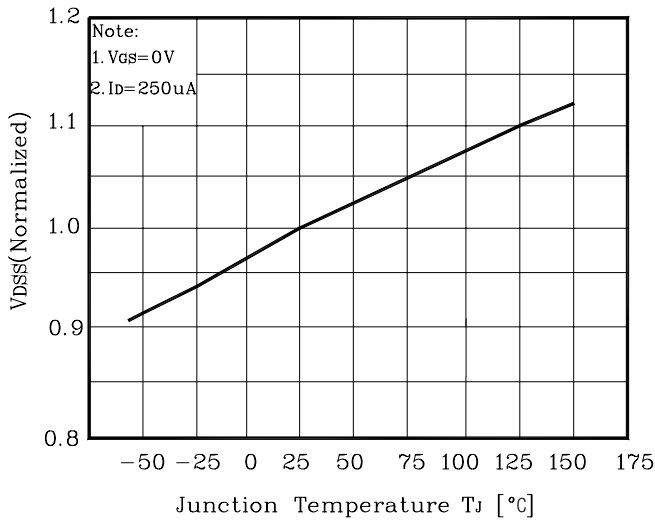
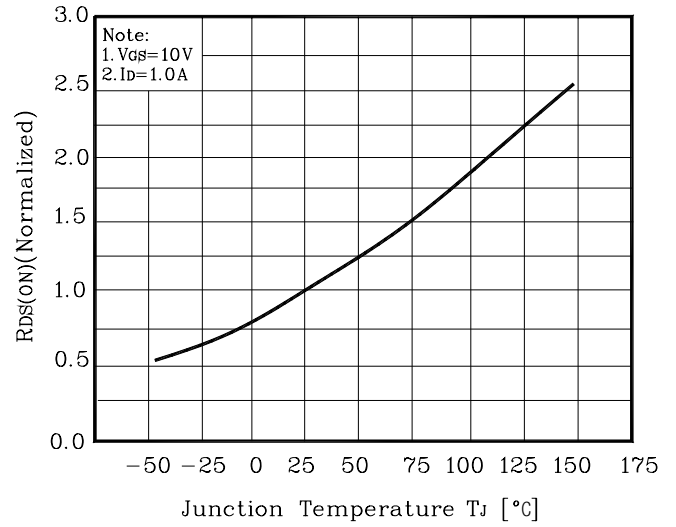
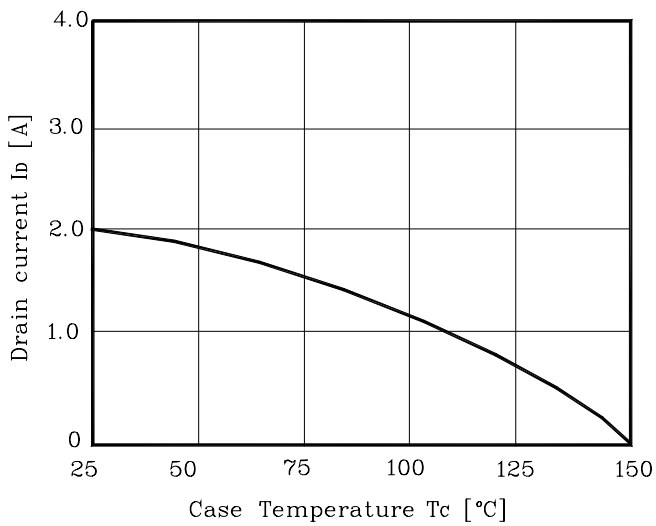
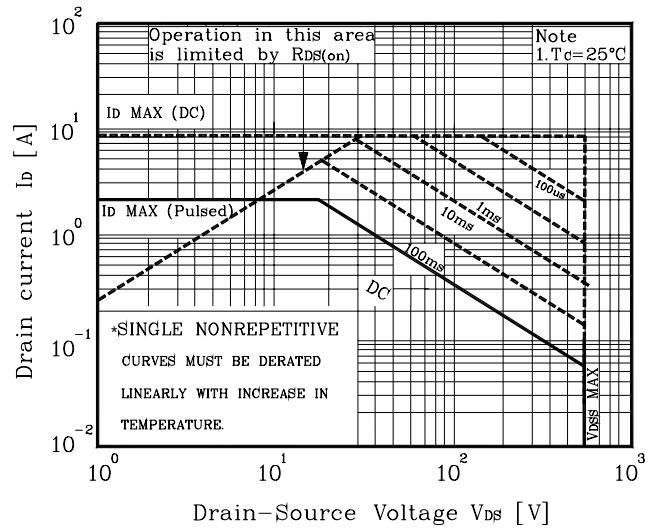
**Source-Drain Diode Ratings and Characteristics** ( $T_C=25^\circ\text{C}$  unless otherwise noted)

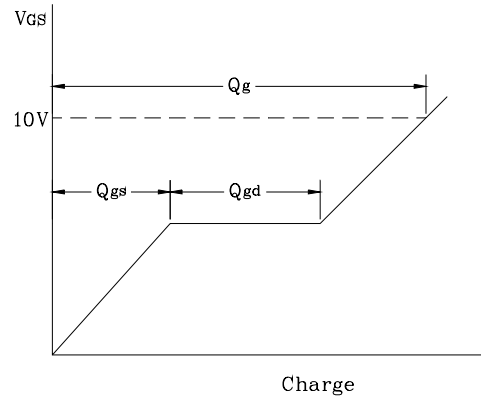
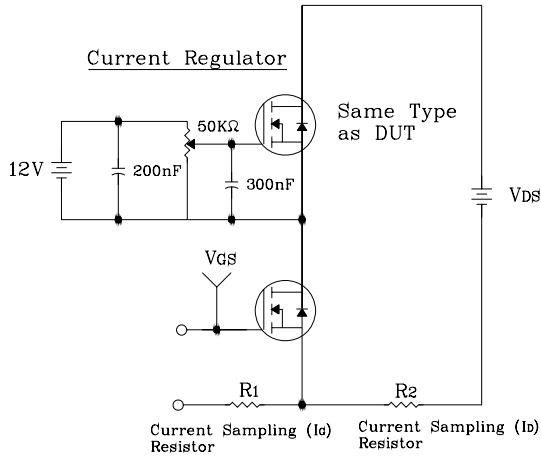
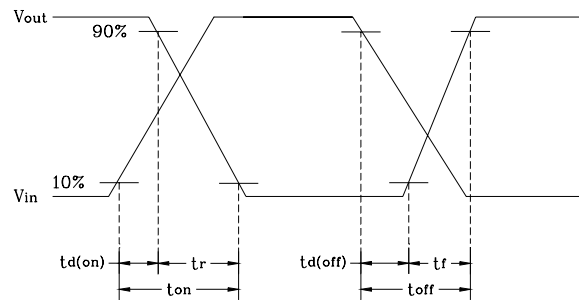
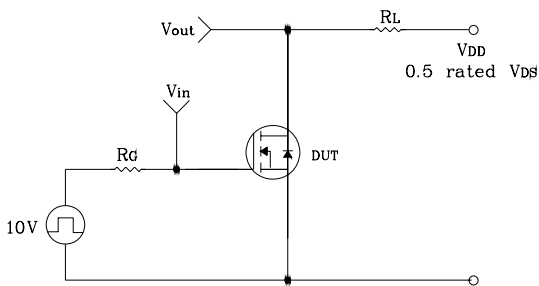
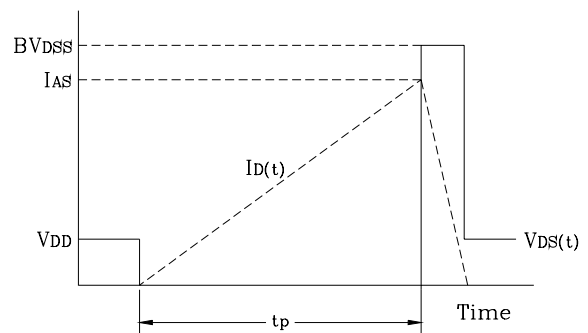
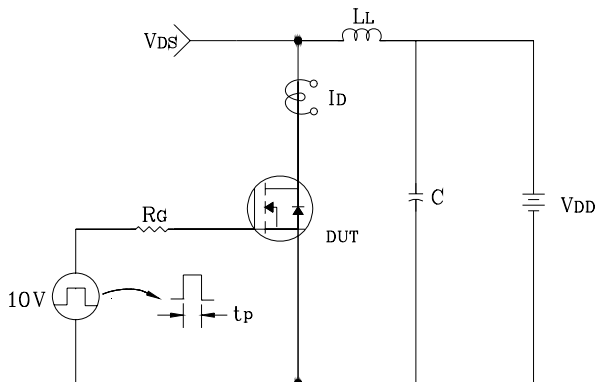
Characteristic Symbol		Test Condition	Min.	Typ.	Max.	Unit
Source current (DC)	$I_S$	Integral reverse diode in the MOSFET	-	-	1.5	A
Source current (Pulsed)	$I_{SM}$		- -		6.0	
Forward voltage	$V_{SD}$	$V_{GS}=0\text{V}, I_S=1.5\text{A}$ -		-	1.5	V
Reverse recovery time	$t_{rr}$	$I_S=1.5\text{A}, V_{GS}=0\text{V}$ $dI_F/dt=100\text{A}/\mu\text{s}$	-	250	-	ns
Reverse recovery charge	$Q_{rr}$		-	550 -		nC

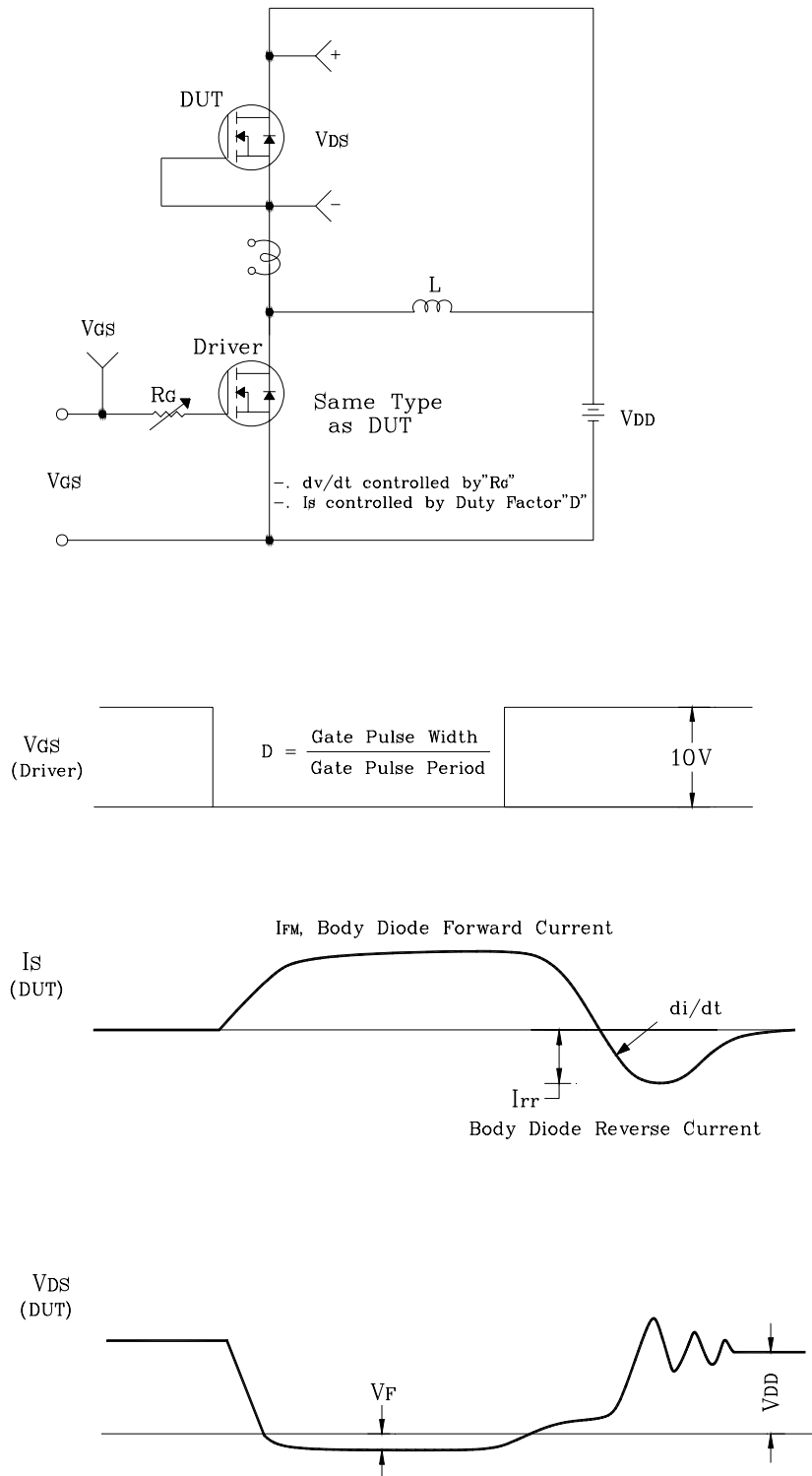
Note ;

- ① Repetitive rating : Pulse width limited by maximum junction temperature
- ②  $L=10.0\text{mH}, I_{AS}=1.5\text{A}, V_{DD}=50\text{V}, R_G=25\Omega,$  Starting  $T_J=25^\circ\text{C}$
- ③ Pulse Test : Pulse width  $\leq 300\mu\text{s}$ , Duty cycle  $\leq 2\%$
- ④ Essentially independent of operating temperature

**Electrical Characteristic Curves**
**Fig. 1  $I_D - V_{DS}$** 

**Fig. 2  $I_D - V_{GS}$** 

**Fig. 3  $R_{DS(on)} - I_D$** 

**Fig. 4  $I_S - V_{SD}$** 

**Fig. 5 Capacitance -  $V_{DS}$** 

**Fig. 6  $V_{GS} - Q_G$** 


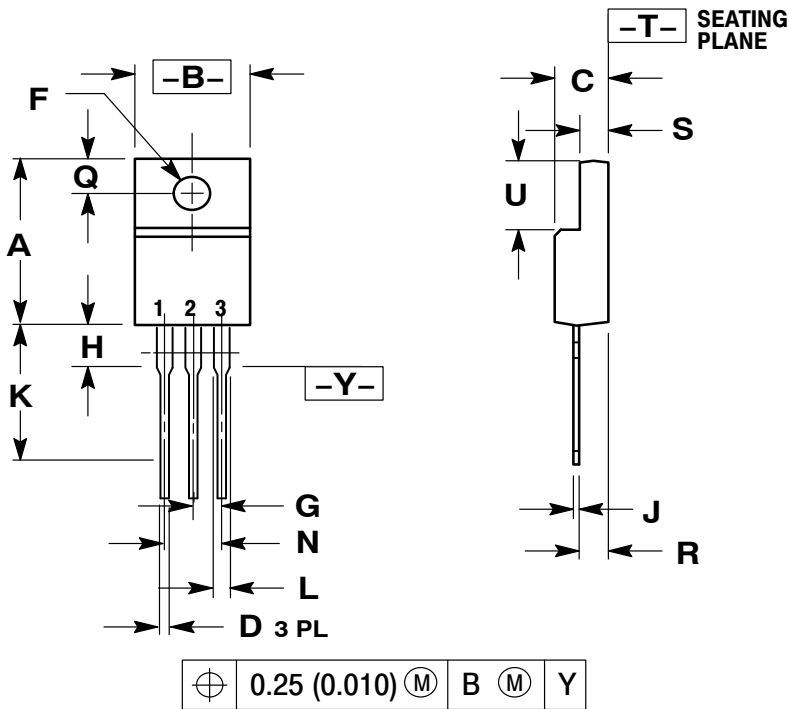
**Electrical Characteristic Curves**
**Fig. 7  $V_{DSS} - T_J$** 

**Fig. 8  $R_{DS(on)} - T_J$** 

**Fig. 9  $I_D - T_C$** 

**Fig. 10 Safe Operating Area**


**Fig. 11 Gate Charge Test Circuit & Waveform**

**Fig. 12 Resistive Switching Test Circuit & Waveform**

**Fig. 13 EAS Test Circuit & Waveform**


**Fig. 14 Diode Reverse Recovery Time Test Circuit & Waveform**


## Package Dimensions

### TO-220F



NOTES:

1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.
2. CONTROLLING DIMENSION: INCH
3. 221D-01 THRU 221D-02 OBSOLETE, NEW STANDARD 221D-03.

DIM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	0.617	0.635	15.67	16.12
B	0.392	0.419	9.96	10.63
C	0.177	0.193	4.50	4.90
D	0.024	0.039	0.60	1.00
F	0.116	0.129	2.95	3.28
G	0.100 BSC		2.54 BSC	
H	0.118	0.135	3.00	3.43
J	0.018	0.025	0.45	0.63
K	0.503	0.541	12.78	13.73
L	0.048	0.058	1.23	1.47
N	0.200 BSC		5.08 BSC	
Q	0.122	0.138	3.10	3.50
R	0.099	0.117	2.51	2.96
S	0.092	0.113	2.34	2.87
U	0.239	0.271	6.06	6.88